Notice of References Cited

Ī	Application/Control No.	Applicant(s)/Pater	nt Under
	10/700,431	Reexamination GUPTA ET AL.	
	Examiner	Art Unit	
ı	TED T. VO	2191	Page 1 of 1

U.S. PATENT DOCUMENTS

	Old First Decometry				
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
	Q					
	R					
	s					
	т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Leach, "Critical Chain Project Management Improves Project Performance", 2000, Advanced Project Institute, Idaho, pp. 1-18.
	v	Leach, "Schedule and Cost Buffer Sizing" , 2002, Advanced Project Institute, Idaho, pp: 1-36.
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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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